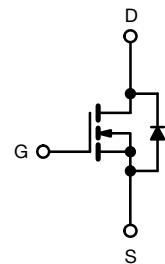
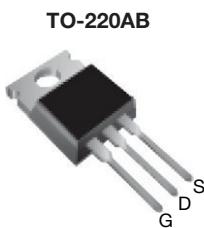


Power MOSFET

PRODUCT SUMMARY		
V_{DS} (V)		250
$R_{DS(on)}$ (Ω)	$V_{GS} = 10$ V	0.19
Q_g max. (nC)		68
Q_{gs} (nC)		11
Q_{gd} (nC)		35
Configuration		Single

FEATURES

- Dynamic dV/dt rating
- Repetitive avalanche rated
- Fast switching
- Ease of paralleling
- Simple drive requirements



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS ($T_C = 25$ °C, unless otherwise noted)

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V_{DS}	250	V
Gate-Source Voltage		± 20	
Continuous Drain Current	I_D	14	A
		8.5	
Pulsed Drain Current ^a	I_{DM}	56	
Linear Derating Factor		1.0	W/°C
Single Pulse Avalanche Energy ^b	E_{AS}	550	mJ
Repetitive Avalanche Current ^a	I_{AR}	14	A
Repetitive Avalanche Energy ^a	E_{AR}	13	mJ
Maximum Power Dissipation	P_D	125	W
Peak Diode Recovery dV/dt ^c		4.8	
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 to +150	°C
Soldering Recommendations (Peak temperature) ^d		300	
Mounting Torque	6-32 or M3 screw	10	lbf · in
		1.1	N · m

Notes

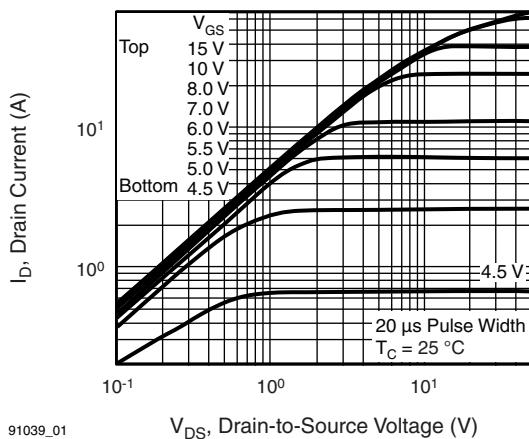
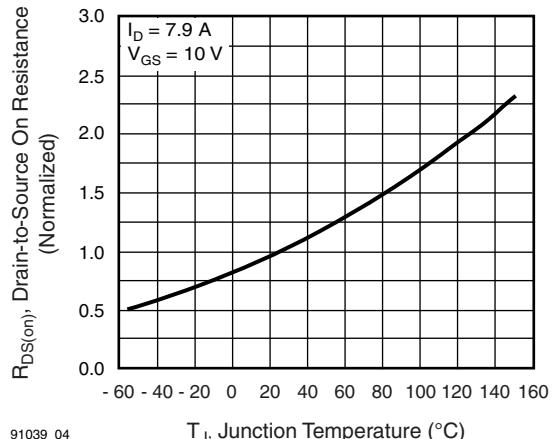
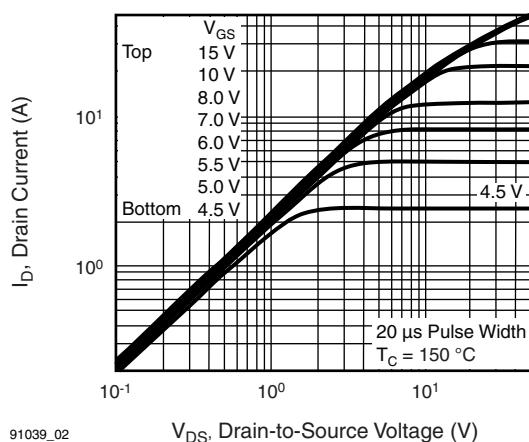
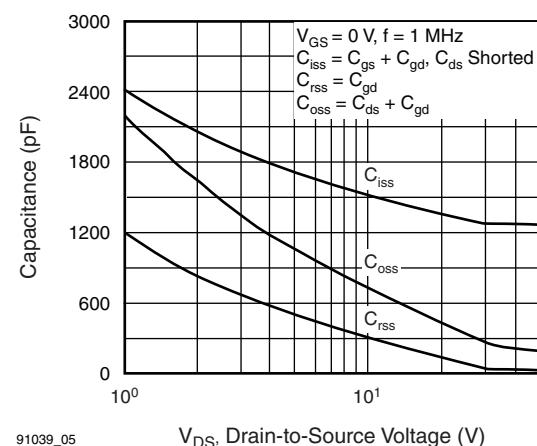
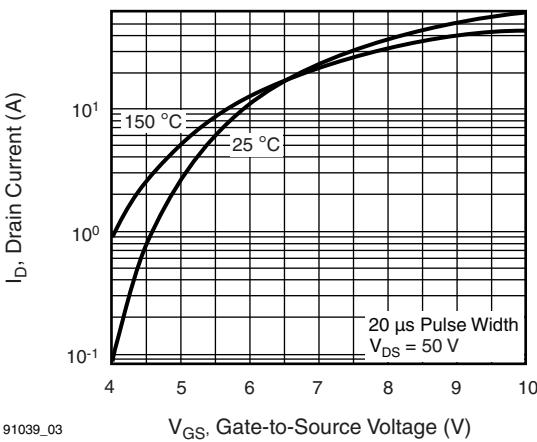
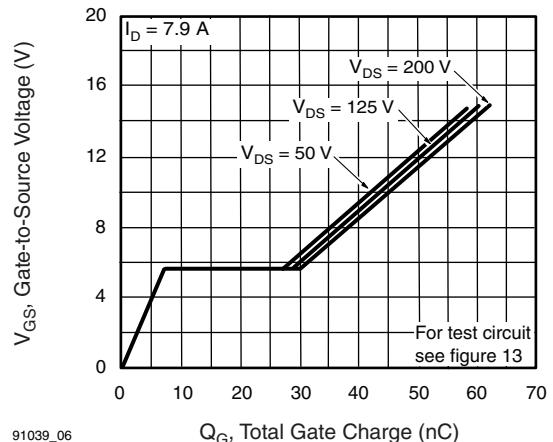
- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- $V_{DD} = 50$ V, starting $T_J = 25$ °C, $L = 4.5$ mH, $R_g = 25$ Ω, $I_{AS} = 14$ A (see fig. 12).
- $I_{SD} \leq 14$ A, $dI/dt \leq 150$ A/μs, $V_{DD} \leq V_{DS}$, $T_J \leq 150$ °C.
- 1.6 mm from case.

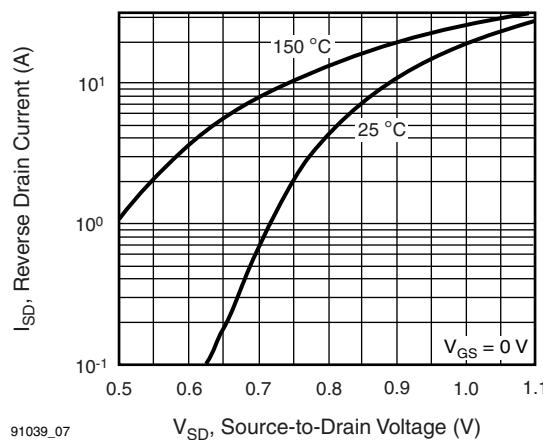
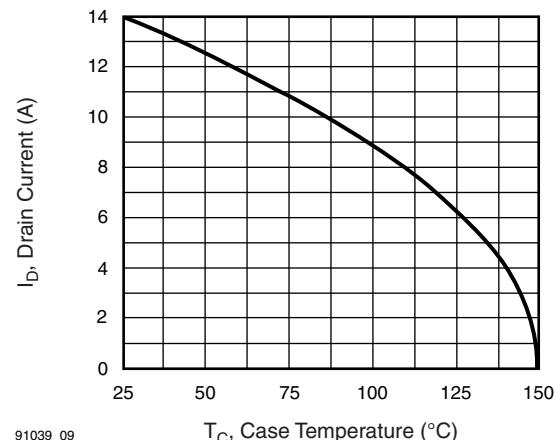
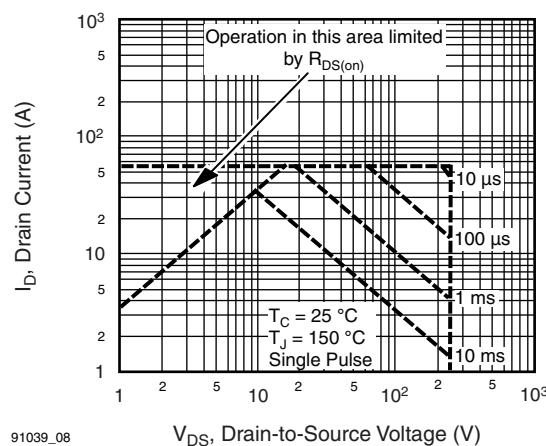
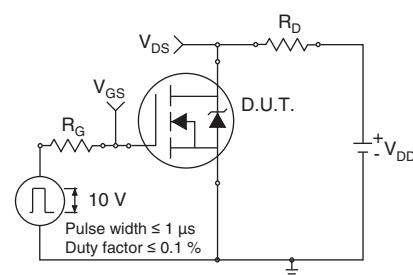
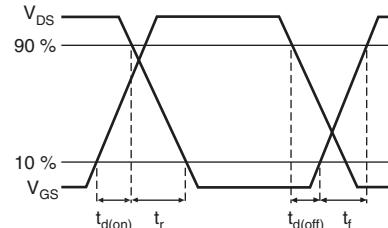
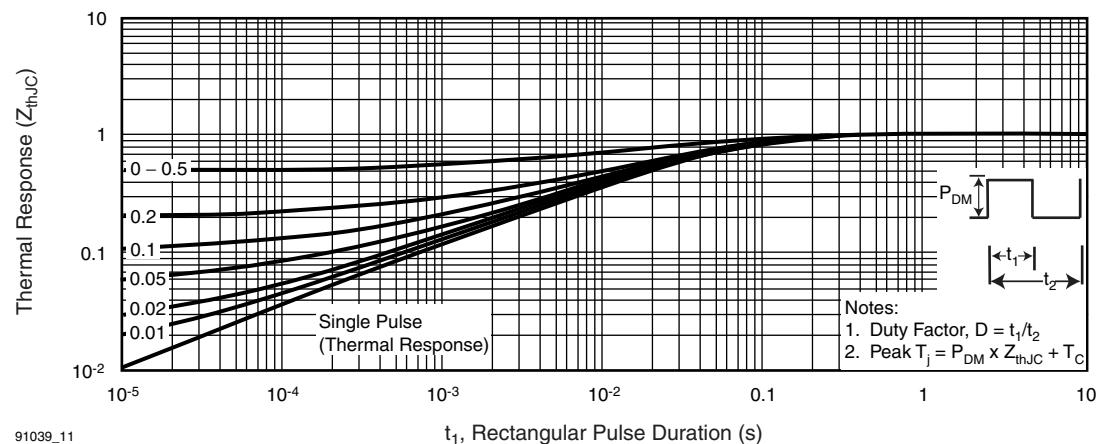
THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	62	$^{\circ}\text{C}/\text{W}$
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.50	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	1.0	

SPECIFICATIONS ($T_J = 25^{\circ}\text{C}$, unless otherwise noted)								
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$		250	-	-	V	
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25°C , $I_D = 1 \text{ mA}$		-	0.34	-	$^{\circ}\text{C}/\text{V}$	
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$		2.0	-	4.0	V	
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 250 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	25	μA	
		$V_{DS} = 200 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 125^{\circ}\text{C}$		-	-	250		
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 8.4 \text{ A}^b$	-	0.19	-	Ω	
Forward Transconductance	g_{fs}	$V_{DS} = 50 \text{ V}$, $I_D = 8.4 \text{ A}^b$		6.7	-	-	S	
Dynamic								
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1.0 \text{ MHz}$, see fig. 5		-	1300	-	pF	
Output Capacitance	C_{oss}			-	330	-		
Reverse Transfer Capacitance	C_{rss}			-	85	-		
Total Gate Charge	Q_g	$V_{GS} = 10 \text{ V}$	$I_D = 7.9 \text{ A}$, $V_{DS} = 200 \text{ V}$, see fig. 6 and 13 ^b	-	-	68	nC	
Gate-Source Charge	Q_{gs}			-	-	11		
Gate-Drain Charge	Q_{gd}			-	-	35		
Turn-On Delay Time	$t_{d(on)}$			-	11	-		
Rise Time	t_r	$V_{DD} = 125 \text{ V}$, $I_D = 7.9 \text{ A}$, $R_g = 9.1 \Omega$, $R_D = 8.7 \Omega$, see fig. 10 ^b		-	24	-	ns	
Turn-Off Delay Time	$t_{d(off)}$			-	53	-		
Fall Time	t_f			-	49	-		
Internal Drain Inductance	L_D			-	4.5	-		
Internal Source Inductance	L_S	Between lead, 6 mm (0.25") from package and center of die contact		-	7.5	-	nH	
Gate Input Resistance	R_g	$f = 1 \text{ MHz}$, open drain		0.3	-	1.2	Ω	
Drain-Source Body Diode Characteristics								
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	14	A	
Pulsed Diode Forward Current ^a	I_{SM}			-	-	56		
Body Diode Voltage	V_{SD}	$T_J = 25^{\circ}\text{C}$, $I_S = 14 \text{ A}$, $V_{GS} = 0 \text{ V}^b$		-	-	1.8	V	
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25^{\circ}\text{C}$, $I_F = 7.9 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	250	500	ns	
Body Diode Reverse Recovery Charge	Q_{rr}			-	2.3	4.6	μC	
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)						

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2 \%$.

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)**Fig. 1 - Typical Output Characteristics, $T_C = 25 \text{ }^\circ\text{C}$** **Fig. 4 - Normalized On-Resistance vs. Temperature****Fig. 2 - Typical Output Characteristics, $T_C = 150 \text{ }^\circ\text{C}$** **Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage****Fig. 3 - Typical Transfer Characteristics****Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage**

**Fig. 7 - Typical Source-Drain Diode Forward Voltage****Fig. 9 - Maximum Drain Current vs. Case Temperature****Fig. 8 - Maximum Safe Operating Area****Fig. 10a - Switching Time Test Circuit****Fig. 10b - Switching Time Waveforms****Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case**

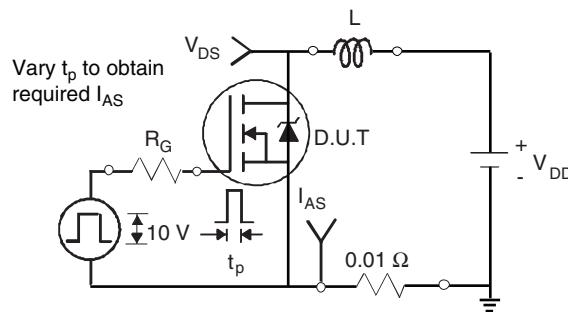


Fig. 12a - Unclamped Inductive Test Circuit

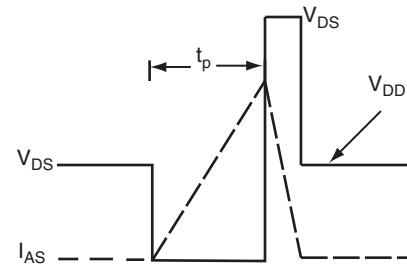


Fig. 12b - Unclamped Inductive Waveforms

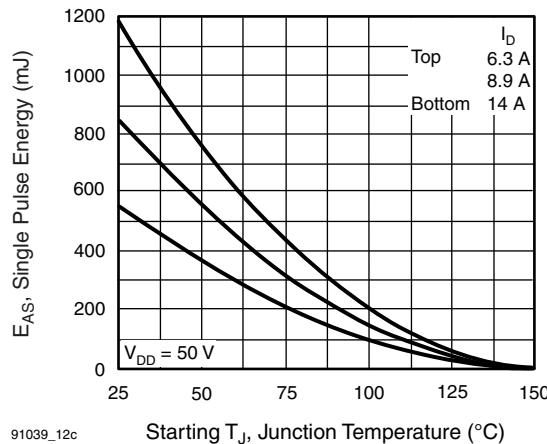


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

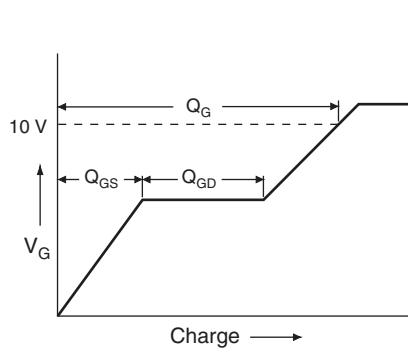


Fig. 13a - Basic Gate Charge Waveform

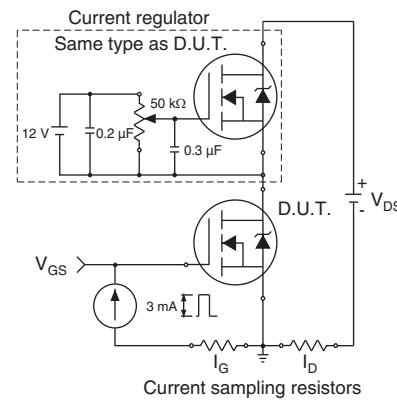
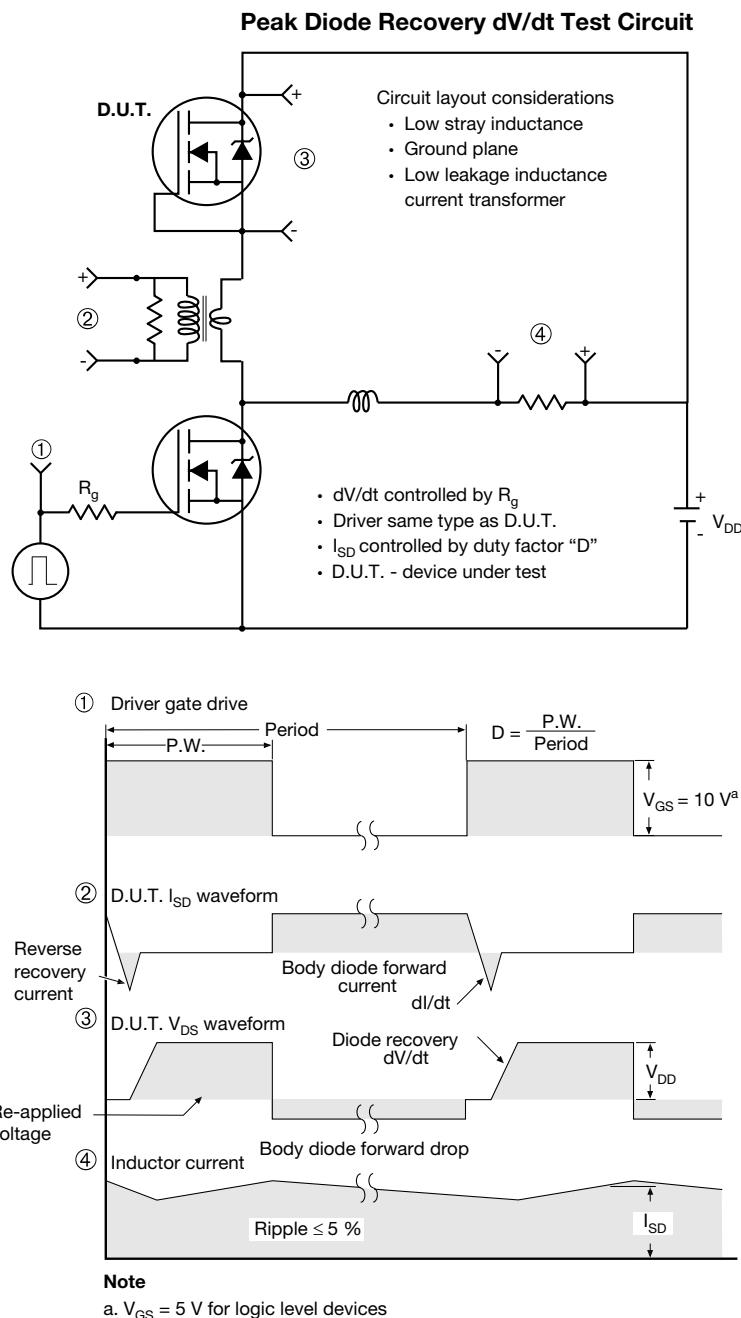
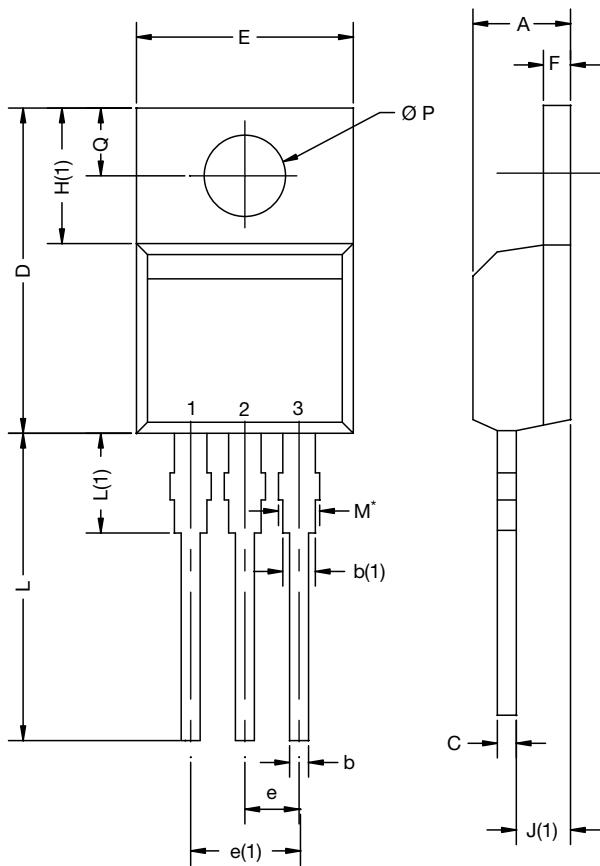


Fig. 13b - Gate Charge Test Circuit

**Fig. 14 - For N-Channel**

TO-220-1

DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	4.24	4.65	0.167	0.183
b	0.69	1.02	0.027	0.040
b(1)	1.14	1.78	0.045	0.070
c	0.36	0.61	0.014	0.024
D	14.33	15.85	0.564	0.624
E	9.96	10.52	0.392	0.414
e	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.10	6.71	0.240	0.264
J(1)	2.41	2.92	0.095	0.115
L	13.36	14.40	0.526	0.567
L(1)	3.33	4.04	0.131	0.159
Ø P	3.53	3.94	0.139	0.155
Q	2.54	3.00	0.100	0.118

ECN: X15-0364-Rev. C, 14-Dec-15
DWG: 6031

Note

- M^* = 0.052 inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM

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